BT258 series

GENERAL DESCRIPTION

Glass passivated, sensitive gate thyristors in a plastic envelope, intended for use in general purpose switching and phase control applications. These devices are intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

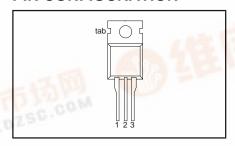
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	MAX.	MAX.	UNIT
V _{DRM} , V _{RRM} I _{T(AV)} I _{T(RMS)} I _{TSM}	Repetitive peak off-state voltages Average on-state current RMS on-state current Non-repetitive peak on-state current	500R 500 5 8 75	600R 600 5 8 75	800R 800 5 8 75	V A A A

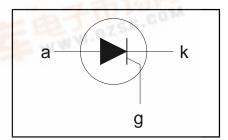
PINNING - TO220AB

PIN	DESCRIPTION			
1	cathode			
2	anode			
3	gate			
tab	anode			

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134).

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SYMBOL	PARAMETER	CONDITIONS	MIN.	da-	MAX.	CCO	UNIT
V_{DRM}, V_{RRM}	Repetitive peak off-state voltages		TE.	-500R 500 ¹	-600R 600 ¹	-800R 800	V
I _{T(AV)} I _{T(RMS)} I _{TSM}	Average on-state current RMS on-state current Non-repetitive peak on-state current	half sine wave; $T_{mb} \le 111$ °C all conduction angles half sine wave; $T_j = 25$ °C prior to surge	-		5 8		A A
l²t dl₁√dt	I ² t for fusing Repetitive rate of rise of on-state current after	t = 10 ms t = 8.3 ms t = 10 ms I _{TM} = 10 A; I _G = 50 mA; dI _G /dt = 50 mA/μs	-	-h=	75 82 28 50	场际	Α Α Α²s Α/μs
I _{GM} V _{GM} V _{RGM} P _{GM} P _{G(AV)} T _{stg} T _j	triggering Peak gate current Peak gate voltage Peak reverse gate voltage Peak gate power Average gate power Storage temperature Operating junction temperature	over any 20 ms period	- - - -40	พพ	2 5 5 5 0.5 150 125 ²		0,0% & < < >

¹ Although not recommended, off-state voltages up to 800V may be applied without damage, but the thyristor may switch to the on-state. The rate of rise of current should not exceed 15 A/ μ s.

² Note: Operation above 110°C may require the use of a gate to cathode resistor of $1k\Omega$ or less.

BT258 series

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
R _{th j-mb}	Thermal resistance		1	1	2.0	K/W
R _{th j-a}	junction to mounting base Thermal resistance junction to ambient	in free air	-	60	-	K/W

STATIC CHARACTERISTICS

T_i = 25 °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I _{GT}	Gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$	-	50	200	μΑ
	Latching current	$V_{\rm D} = 12 \text{ V}; I_{\rm GT} = 0.1 \text{ A}$	-	0.4	10	mΑ
I _H	Holding current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$	-	0.3	6	mΑ
Ϊ́Τ	On-state voltage	$I_{T} = 16 \text{ A}$	-	1.3	1.5	V
V _{GT}	Gate trigger voltage	$\dot{V}_{D} = 12 \text{ V}; I_{T} = 0.1 \text{ A}$	-	0.4	1.5	V
"		$V_{\rm D} = V_{\rm DRM(max)}$; $I_{\rm T} = 0.1 \text{ A}$; $T_{\rm i} = 110 ^{\circ}\text{C}$	0.1	0.2	-	V
I_D, I_R	Off-state leakage current	$V_D = V_{DRM(max)}^{SKM(max)}; V_R = V_{RRM(max)}; T_j = 125 °C$	-	0.1	0.5	mA

DYNAMIC CHARACTERISTICS

 $T_i = 25$ °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
dV _D /dt	Critical rate of rise of off-state voltage	V_{DM} = 67% $V_{DRM(max)}$; T_j = 125 °C; exponential waveform; R_{GK} = 100 Ω	50	100	1	V/μs
t _{gt}	Gate controlled turn-on time	$I_{TM} = 10 \text{ A}; V_D = V_{DRM(max)}; I_G = 5 \text{ mA};$ $dI_G/dt = 0.2 \text{ A}/\mu\text{s}$	-	2	-	μs
t _q	Circuit commutated turn-off time	$\begin{array}{l} V_{\text{D}} = 67\% \ V_{\text{DRM(max)}}; \ T_{j} = 125 \ ^{\circ}\text{C}; \\ I_{\text{TM}} = 12 \ A; \ V_{\text{R}} = 24 \ V; \ dI_{\text{TM}}/dt = 10 \ A/\mu s; \\ dV_{\text{D}}/dt = 2 \ V/\mu s; \ R_{\text{GK}} = 1 \ k\Omega \end{array}$	-	100	-	μs

BT258 series

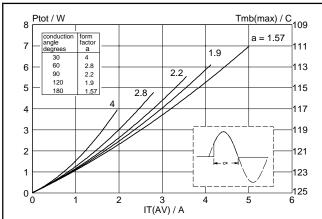


Fig.1. Maximum on-state dissipation, P_{tot} , versus average on-state current, $I_{T(AV)}$, where $a = form \ factor = I_{T(RMS)}/I_{T(AV)}$.

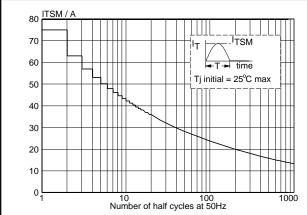


Fig.4. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus number of cycles, for sinusoidal currents, f = 50 Hz.

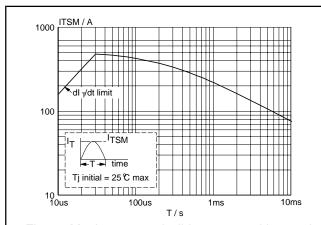


Fig.2. Maximum permissible non-repetitive peak on-state current I_{TSM} , versus pulse width t_p , for sinusoidal currents, $t_p \le 10$ ms.

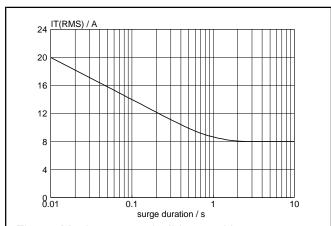


Fig.5. Maximum permissible repetitive rms on-state current $I_{T(RMS)}$, versus surge duration, for sinusoidal currents, f = 50 Hz; $T_{mb} \le 111$ °C.

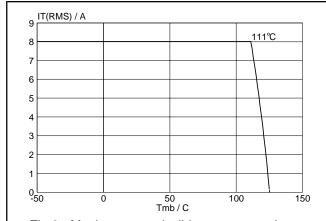


Fig.3. Maximum permissible rms current $I_{T(RMS)}$, versus mounting base temperature T_{mb} .

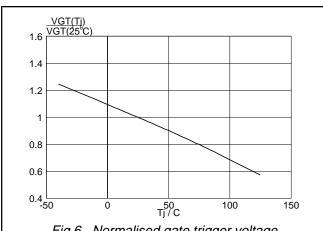
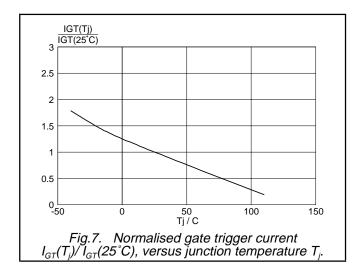
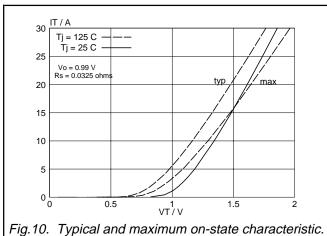
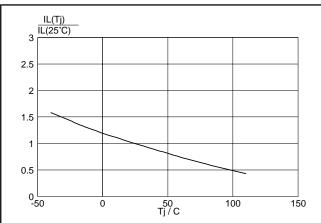


Fig.6. Normalised gate trigger voltage $V_{GT}(T_j)/V_{GT}(25^{\circ}C)$, versus junction temperature T_j .

BT258 series







Normalised latching current $I_L(T_i)/I_L(25^{\circ}C)$, versus junction temperature T_j .

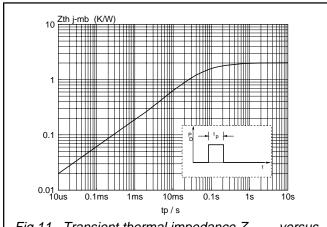


Fig.11. Transient thermal impedance $Z_{th j \cdot mb}$, versus pulse width t_p .

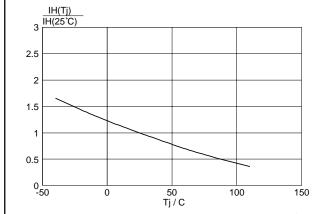


Fig.9. Normalised holding current $I_H(T_i)/I_H(25^{\circ}C)$, versus junction temperature T_i .

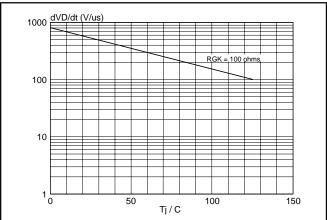
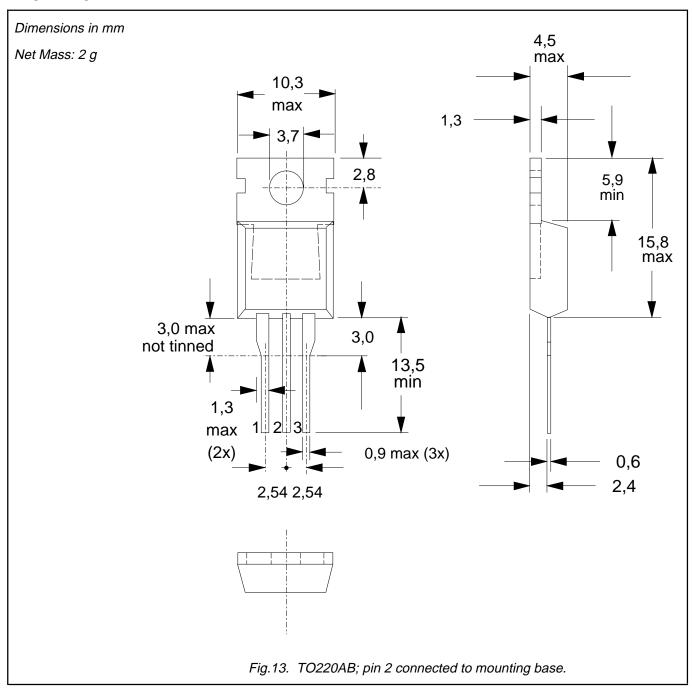


Fig.12. Typical, critical rate of rise of off-state voltage, dV_D/dt versus junction temperature $T_{j\cdot}$

BT258 series

MECHANICAL DATA



- Notes
 1. Refer to mounting instructions for TO220 envelopes.
 2. Epoxy meets UL94 V0 at 1/8".

Philips Semiconductors Product specification

Thyristors logic level

BT258 series

DEFINITIONS

Data sheet status					
Objective specification	This data sheet contains target or goal specifications for product development.				
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.				
Product specification	This data sheet contains final product specifications.				
1 reduct op comeditors	This data direct contains intal product openingations.				

Limiting values

Limiting values are given in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of this specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information

Where application information is given, it is advisory and does not form part of the specification.

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